Serial No. : 09/941,396
Filed   : August 28, 2001

IN THE SPECIFICATION:

Please amend the specification as follows:

(1) The paragraph from page 10, line 9 to page 10, line 13 has been amended as follows:

In the previous applications owned by the same assignee of this invention, an event based test system is described in U.S. Patent Application Nos. 09/406,300 (now U.S. Patent No. 6,532,561) and 09/340,371 (now U.S. Patent No. 6,678,643) "Event based semiconductor test system" and an event based design validation station is described in U.S. Patent Application No. 09/428,746 (now U.S. Patent No. 6,678,645) "Method and apparatus for SoC design validation". Further, a time scaling technology is described in U.S. Patent Application No. 09/286,226 (now U.S. Patent No. 6,557,133) "Scaling logic for Event Based Test System". All of these patent applications are incorporated by reference.